

FORM PTO-1449 (REV. 7-80)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. TEWES ET AL PCT		SERIAL NO. 09/319,092		
LIST OF REFERENCES CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT MICHAEL TEWES ET AL				
				FILING DATE JUNE 18, 1999		GROUP 2878		
U.S. PATENT DOCUMENTS								
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
	AA	5,296,700	8/1994	Kumagai				
	AB							
	AC							
	AD							
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FOREIGN PATENT DOCUMENTS								
		DOCUMENT NUMBER	DATE	COUNTRY	CLAS S	SUBCLASS	TRANSLATION	
							YES	NO
	AL	0-731-371	03-1995	European appln.				
SL	AM	0 941 470	^{9/1999} 11/1997	European appln.				✓
SL	AN	WO 90/01716	^{2/1990} 08/1989	International				
	AO	WO-94/16313	01-1994	International				
	AP							
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)								
	AR	✓	"Mikroskopgestuetzte-Fluoreszenz-Photonen-Korrelation"- by M. Völeker et al, <u>Technisches Messen</u> 63 (1996) Oldenbourg					
SL	AS	✓	"Fluoreszenz-Korrelations-Spektrometer" April 1996, Carl Zeiss Jena GmbH					
EXAMINER SL hu				DATE CONSIDERED 1/5/03				

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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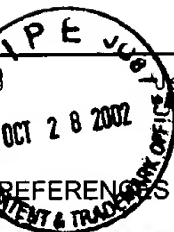
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
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OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

	AR	✓	History of Leica Confocal Microscope System
SL	AS	✓	Fluorescence lifetime measurements using a novel fiber-optic laser.. K.P. Ghiggino et al, <i>Rev. Sci Instrum</i> 63(5) 2998-3002, May 1992 University of Melbourne, Australia 4/22/92
	AT	✓	Improved fluorescence correlation apparatus for precise... J. Schneider et al, University of Berne, Switzerland Dec 14, 1987

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LIST OF REFERENCES CITED BY APPLICANT

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—	AR	✓	Dual-Color Fluorescence Cross-Correlation Spectroscopy for Multi-
			component ... P. Schwille et al Biophysical Journal Vol. 72 Apr. 1997
—	AS	✓	Handbook of Biological Confocal Microscopy - D.R. Sandison et al
			Plenum Press, New York, 1985
SL	AT	✓	Scanning Concentration Correlation Spectroscopy using ...
			D. E. Koppel et al, Biophysical Journal 66 p 502-507, February 1994 Univ. of Connecticut, Farmington, Conn. 1994

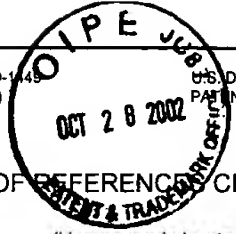
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51	✓		Analysis of confocal laser-microscope optics for 3-D fluorescence...
	AR		Hong Qian et al - Applied Optics, Apr. 1, 1991, vol. 30, No. 10 ¹¹⁸⁵⁻¹¹⁹⁵
	✓		Fluorescence-Correlation-Spectroscopy by N. Thompson
	AS		Univ. of N.C. Chapel Hill, N.C. - Plenum Press, NY 1991
	AT		

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